

Special Issue

Condition Monitoring and the Safety of Industrial Processes

Message from the Guest Editors

This Special Issue aims to bring together the recent advances in innovative techniques for improving the safety of industrial processes. The scope of this Special Issue includes, but is not limited to, the following topics:

- Fault detection;
- Fault diagnosis;
- Fault prognosis;
- Process monitoring;
- Multivariate statistical process control;
- Machine learning for process safety;
- Fault tolerant control.

Guest Editors

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Deadline for manuscript submissions

closed (31 July 2025)



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Message from the Editor-in-Chief

You are invited to contribute either a research article or a comprehensive review for consideration and publication in *Processes* (ISSN 2227-9717). *Processes* is published in open access format – research articles, reviews, and other content are released on the internet immediately after acceptance. The scientific community and the general public have unlimited, free access to the content. As an open access journal, *Processes* is supported by the authors and their institutes through the payment of article processing charges (APCs) for accepted papers. We would be pleased to welcome you as one of our authors.

Editor-in-Chief

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